

IRFR330B / IRFU330B

400V N-Channel MOSFET

General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies and electronic lamp ballasts based on half bridge.

Features

- 4.5A, 400V, $R_{DS(on)} = 1.0\Omega$ @V_{GS} = 10 V Low gate charge (typical 25 nC)
- Low Crss (typical 20 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability



Absolute Maximum Ratings $T_C = 25$ °C unless otherwise noted

Symbol	Parameter		IRFR330B / IRFU330B	Units
V_{DSS}	Drain-Source Voltage		400	V
I _D	Drain Current - Continuous (T _C = 25°	°C)	4.5	Α
	- Continuous (T _C = 100	O°C)	2.9	А
I _{DM}	Drain Current - Pulsed	(Note 1)	18	Α
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	330	mJ
I _{AR}	Avalanche Current	(Note 1)	4.5	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	4.8	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns
P _D	Power Dissipation (T _A = 25°C) *		2.5	W
	Power Dissipation (T _C = 25°C)		48	W
	- Derate above 25°C	T T	0.38	W/°C
T _J , T _{stg}	Operating and Storage Temperature Rai	nge	-55 to +150	°C
T _L	Maximum lead temperature for soldering 1/8" from case for 5 seconds	g purposes,	300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.6	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	i	Min	Тур	Max	Units
Off Cha	racteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		400			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced	to 25°C	-	0.4		V/°C
I _{DSS}	Zana Cata Valta na Dunia Commant	V _{DS} = 400 V, V _{GS} = 0 V				10	μΑ
	Zero Gate Voltage Drain Current	V _{DS} = 320 V, T _C = 125°C	;			100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 2.25 A			0.83	1.0	Ω
g _{FS}	Forward Transconductance	$V_{DS} = 40 \text{ V}, I_{D} = 2.25 \text{ A}$	(Note 4)	-	3.9		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			790 80 20	1000 100 26	pF pF pF
	ng Characteristics				20	20	рг
t _{d(on)}	Turn-On Delay Time	V 200 V I 5 5 A			15	40	ns
t _r	Turn-On Rise Time	$V_{DD} = 200 \text{ V}, I_D = 5.5 \text{ A},$			55	120	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 25 \Omega$			85	180	ns
t _f	Turn-Off Fall Time		(Note 4, 5)		50	110	ns
Q _g	Total Gate Charge	V _{DS} = 320 V, I _D = 5.5 A,			25	33	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V			4.3		nC
Q _{gd}	Gate-Drain Charge		(Note 4, 5)		11		nC
	ource Diode Characteristics a	nd Maximum Rating	S				
I _S	Maximum Continuous Drain-Source Did	ode Forward Current				4.5	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F					18	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 4.5 \text{ A}$				1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 5.5 \text{ A},$			265		ns
Q _{rr}	Reverse Recovery Charge	dl _F / dt = 100 A/μs	(Note 4)		2.32		μC

- Notes:
 1. Repetitive Rating : Pulse width limited by maximum junction temperature
 2. L = 28.5mH, I $_{AS}$ = 4.5A, V $_{DD}$ = 50V, R $_{G}$ = 25 Ω, Starting T $_{J}$ = 25°C
 3. I $_{SD}$ ≤ 5.5A, di/dt ≤ 300A/μs, V $_{DD}$ ≤ BV $_{DSS}$, Starting T $_{J}$ = 25°C
 4. Pulse Test : Pulse width ≤ 300 μ s, Duty cycle ≤ 2%
 5. Essentially independent of operating temperature

Typical Characteristics

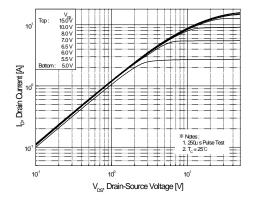


Figure 1. On-Region Characteristics

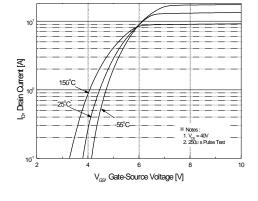


Figure 2. Transfer Characteristics

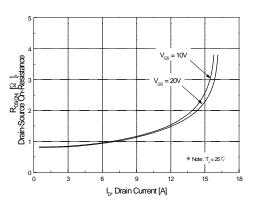


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

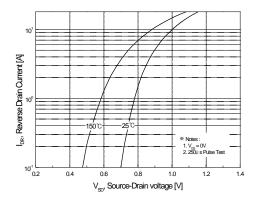


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

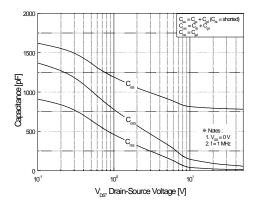


Figure 5. Capacitance Characteristics

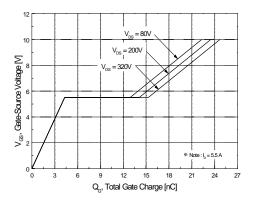


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

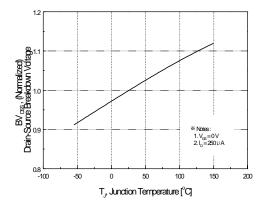


Figure 7. Breakdown Voltage Variation vs Temperature

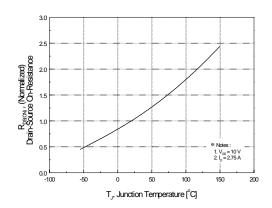


Figure 8. On-Resistance Variation vs Temperature

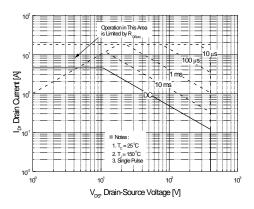


Figure 9. Maximum Safe Operating Area

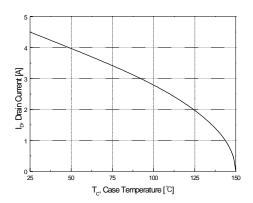


Figure 10. Maximum Drain Current vs Case Temperature

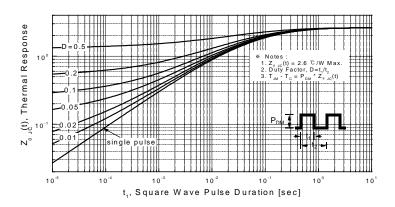
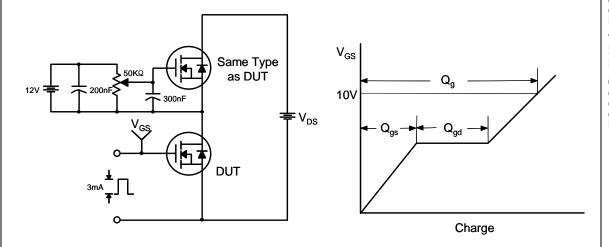


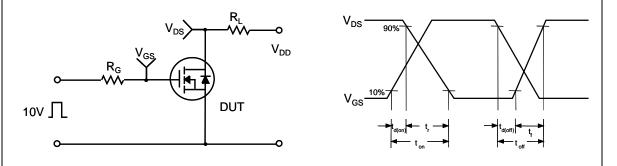
Figure 11. Transient Thermal Response Curve

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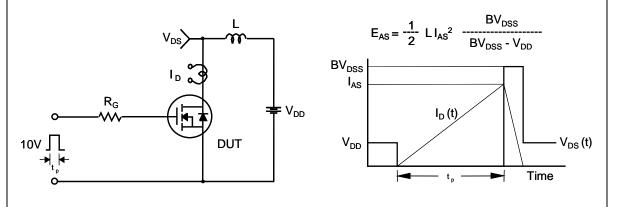
Gate Charge Test Circuit & Waveform



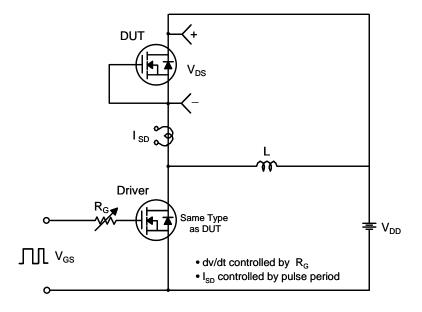
Resistive Switching Test Circuit & Waveforms

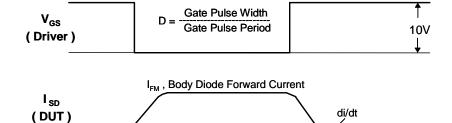


Unclamped Inductive Switching Test Circuit & Waveforms



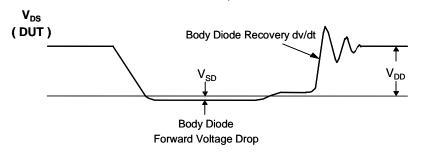
Peak Diode Recovery dv/dt Test Circuit & Waveforms



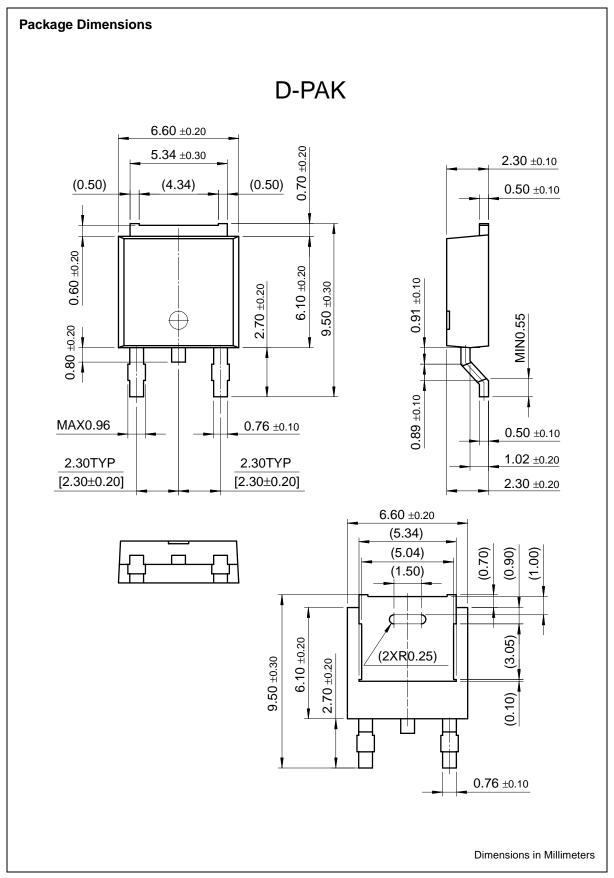


Body Diode Reverse Current

 I_{RM}

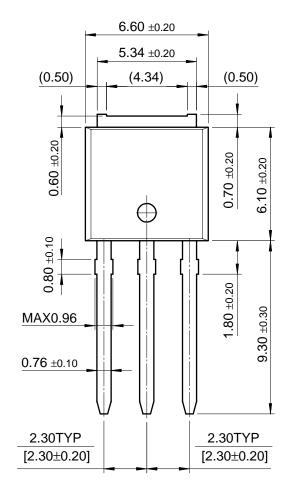


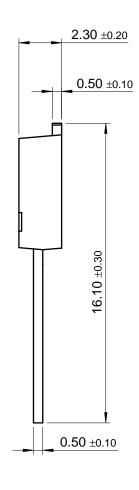
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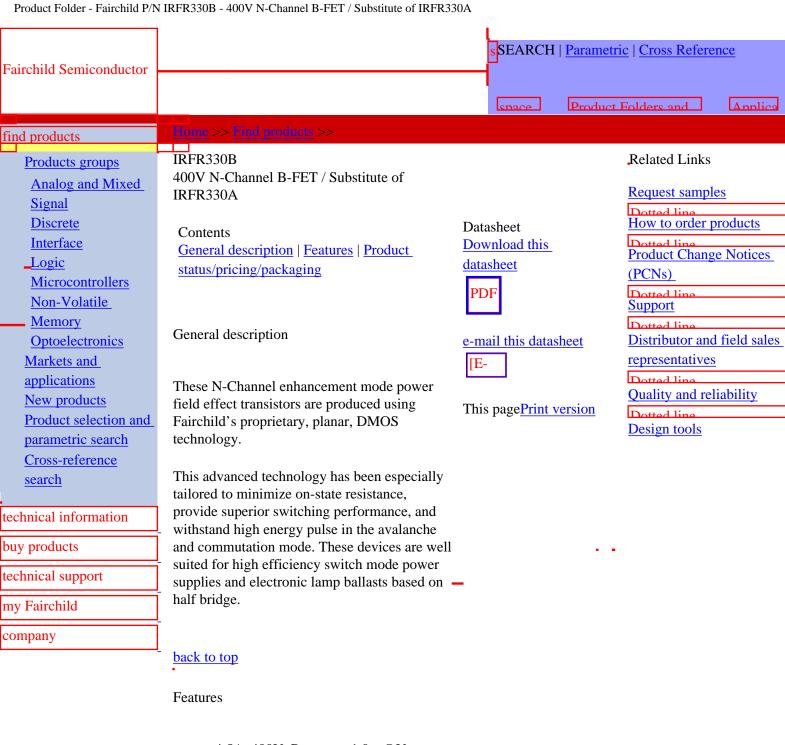
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Datasheet Identification	Product Status	Definition
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- 4.5A, 400V, $R_{DS(on)} = 1.0\Omega$ @ $V_{GS} = 10V$
- Low gate charge (typical 25 nC)
- Low Crss (typical 20 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

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Product status/pricing/packaging

Product	Product status	Pricing*	Package type	Leads	Packing method	
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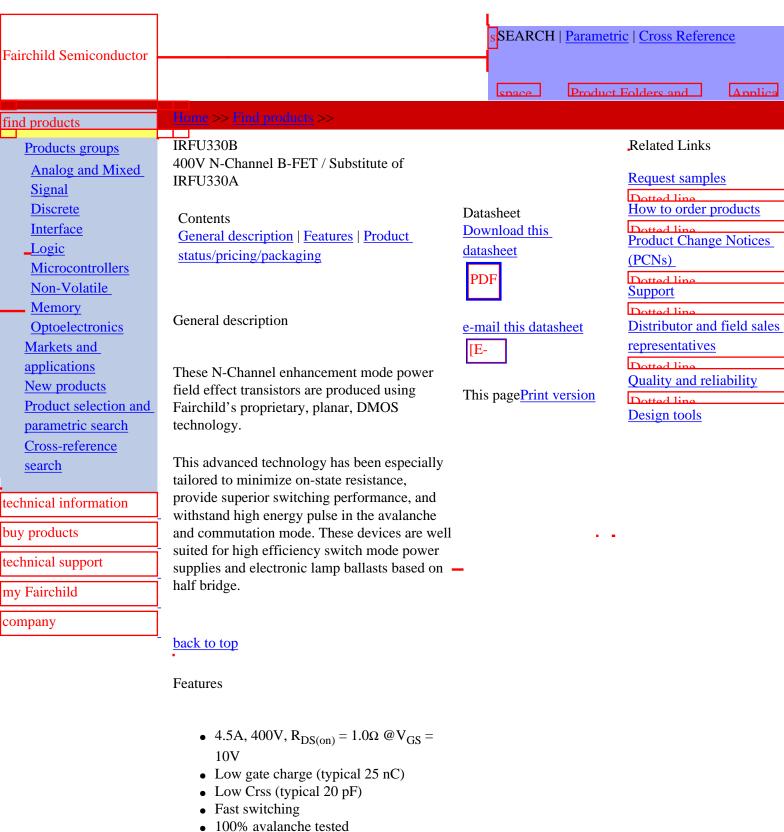
IRFR330BTM	Full Production	\$0.62	TO-252(DPAK)	2	TAPE REEL
IRFR330BTF	Full Production	\$0.62	TO-252(DPAK)	2	TAPE REEL

^{* 1,000} piece Budgetary Pricing

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• Improved dv/dt capability

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Product status/pricing/packaging

	Product	Product status	Pricing*	Package type	Leads	Packing method	l
- 1				0 0 1			- 1

Product Folder - Fairchild P/N IRFU330B - 400V N-Channel B-FET / Substitute of IRFU330A

IRFU330BTU	Full Production	\$0.62	TO-251(IPAK)	3	RAIL

^{* 1,000} piece Budgetary Pricing

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